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SPECKLE 2015: VI International Conference on Speckle Metrology

**Fernando Mendoza Santoyo
Eugenio R. Méndez**
Editors

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Introduction

Welcome to Mexico and the colonial city of Guanajuato, a UNESCO-designated World Heritage Site. This historical city, with its colors and its network of winding streets, has been chosen as the venue of the Sixth International Conference on Speckle Metrology (SPECKLE 2015). With participants coming from more than 20 different countries, the conference is a truly international event that forms part of Mexico's celebrations for the International Year of Light (IYL).

The conference is the latest of a series of meetings devoted to speckle phenomena and their wide range of applications. The goal of this conference is to gather scientists, engineers and students who work in the field of speckle metrology and related techniques, and provide a stimulating environment for discussions. We believe that the conference will provide a good picture of the state of the field and indicate new directions for future research. In this sense, the Conference Chairs encouraged the submission of papers on topics that were not included in the past, like the use of the speckle in spectroscopy, imaging through scattering media and biological sciences. The works will be presented in eight oral sessions and one poster session, for a total of 71 papers that cover subjects like speckle statistics, speckle interferometry, digital techniques in speckle, dynamic laser speckle, interaction of light with random media, and imaging and spectroscopic techniques involving speckle.

We encourage you to contribute to the exchange of up-to-date information in your fields of expertise and share your latest achievements with your colleagues. The meeting should be an opportunity to discuss with old friends and establish new contacts. Hopefully, it will be the starting point of many new joint ventures and research projects. Your active participation will contribute to the atmosphere that we are trying to promote.

We hope you enjoy the meeting.

Fernando Mendoza Santoyo
Eugenio R. Méndez

